Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/772,595	BOKISA ET AL.	
Examiner	Art Unit	
Edna Wong	1753	

`	SEAR	CHED	
Class	Subclass	Date	Examiner
205	238	5/17/2005	EW
205	239	5/17/2005	EW
205	240	5/17/2005	EW
205	241	5/17/2005	EW.
205	242	5/17/2005	EW
205	244	5/17/2005	EW
205	245	5/17/2005	EW
205	246	5/17/2005	EW
205	247	5/17/2005	EW
205	250	5/17/2005	EW
205	251 ⁻	5/17/2005	EW
* 205	252	5/17/2005	EW
205	253	5/17/2005	EW
205	254	5/17/2005	EW

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
			-
	<u> </u>		

SEAR((INCLUDING SE	CH NOTES ARCH STRATE	GY)
·	DATE	EXMR
Inventor Search	5/17/200	5 EW
EAST	5/17/200	5 EW
STN	5/17/200	5 EW

Search Notes (continued)

Application/Control No.	Applicant(s)/Patent under Reexamination
10/772,595	BOKISA ET AL.
Examiner	Art Unit
Edna Wong	1753

	SEAR	CHED	
Class	Subclass	Date	Examiner
205	255	5/17/2005	EW
205	257	5/17/2005	EW
205	259	5/17/2005	EW
205	260	5/17/2005	EW

INT	ERFERENC	CE SEARCH	ED
Class	Subclass	Date	Examiner

SEARCH N (INCLUDING SEARC	SEARCH NOTES (INCLUDING SEARCH STRATEGY)	
	DATE	EXMR
	,	
		_
	•	
		ļ
·		